



U.S. Department of Commerce Patent and Trademark Office					ATTY DOCKET NO.	SERIAL NO.	
					BMID 9958 CIP US		10/601,144
					APPLICANT BHULLAR et al.		
INFORMATION DISCLOSURE STATEMENT					FILING DATE	GROUP	
					06/20/2003	1243 3700	
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date
cg	1	4,081,653	3-28-1978	Koo et al.	219	121	
	2	4,131,484	12-26-78	Caruso, et al.	134	1	
	3	4,414,059	11-8-83	Blum et al.	156	659.1	
	4	4,684,437	8-4-1987	Donelon et al.	156	643	
	5	4,865,873	9-12-1989	Cole et al.	427	53.1	
	6	4,874,500	10-17-89	Madou et al.	204	412	
	7	4,897,173	1-30-90	Nankai et al.	204	403	
	8	5,018,164	5/21/91	Brewer et al.	372	109	
	9	5,089,103	2-18-92	Swedberg	204	182.8	
	10	5,104,480	4-14-92	Wojnarowski et al.	156	643	
	11	5,120,420	6-9-92	Nankai et al.	204	403	
	12	5,264,103	11/93	Yoshioka et al.	204	403	
	13	5,266,179	11-30-93	Nankai et al.	204	401	
	14	5,288,636	2-22-94	Pollmann et al.	435	288	
	15	5,334,279	8-2-94	Gregoire	156	630	
	16	5,336,388	8-9-94	Leader et al.	204	406	
	17	5,382,346	1-17-95	Uenoyama et al.	204	403	
	18	5,390,412	2-21-95	Gregoire	29	848	
	19	5,391,250	2-21-95	Cheney II et al.	156	268	
	20	5,395,504	3-7-95	Saurer et al.	204	403	
	21	5,413,690	5-9-95	Kost et al.	204	403	
	22	5,414,224	5-9-95	Adasko et al.	174	262	
	23	5,426,850	6-27-95	Fukutomi et al.	29	848	
	24	5,437,999	5-13-97	Diebold et al.	435	288	
	25	5,451,722	9-19-95	Gregoire	174	261	
	26	5,465,480	11-14-95	Karl et al.	29	825	
	27	5,496,453	3-5-96	Uenoyama et al.	205	777.5	
	28	5,508,171	4-16-96	Walling et al.	205	777.5	
	29	5,509,410	4-23-96	Hill et al.	128	637	
	30	5,512,489	04-1996	Girault et al.	205	777.5	
	31	5,575,930	11-19-96	Tietje-Girault et al.	216	65	
	32	5,576,073	11-19-96	Kickelhain	427	555	
	33	5,589,326	12-31-96	Deng et al.	435	4	
	34	5,593,739	1-14-97	Kickelhain	427	555	
	35	5,628,890	5-13-97	Carter et al.	204	403	
	36	5,635,054	06-1997	Girault et al.	205	775	
	37	5,682,884	11-4-97	Hill et al.	128	637	
	38	5,708,247	1-13-98	McAleer et al.	204	403	
	39	5,755,953	5-26-98	Henning et al.	205	778	
	40	5,773,319	6-30-98	Chu et al.	438	39	
	41	5,739,039	04-1998	Girault et al.	436	149	
	42	5,758,398	6-2-98	Rijnbeek et al	29	25.42	
	43	5,759,364	6-2-98	Charlton et al.	204	403	
	44	5,762,770	6-9-98	Pritchard et al.	204	403	
	45	5,798,031	8-25-98	Charlton et al.	204	403	
	46	5,948,289	09-07-99	Noda et al.	219	121.69	
	47	5,955,179	9/99	Kickelhain et al.	428	210	
cg	48	5,956,572	9-21-99	Kidoguchi et al.	438	96	
Examiner <i>Gales</i>					Date Considered <i>11/17/05</i>		

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				APPLICANT BHULLAR et al.			
				FILING DATE 06/20/2003	GROUP 1743 37 ac		
INFORMATION DISCLOSURE STATEMENT							

*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date
Qm	5,965,001	10-12-99	Chow et al.	204	600	
Qm	6,004,441	12-21-99	Fujiwara et al.	204	412	
Qm	6,103,033	8-15-00	Say et al.	156	73.1	
Qm	6,134,461	10-17-00	Say et al.	600	345	
Qm	6,165,594	12-26-00	Moh et al.	428	207	
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Qm	6,203,952 B1	3-20-01	O'Brien et al.	430	17	
Qm	6,258,229 B1	7-01	Winarta et al.	205	403	
Qm	6,287,451 B1	9-11-01	Winarta et al.	205	777.5	
Qm	6,299,757 B1	10-9-01	Feldman et al.	205	775	
Qm	6,309,526 B1	10-30-01	Fujiwara et al.	204	403	
Qm	6,338,790 B1	1-15-02	Feldman et al.	205	777.5	
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Qm	0 480 703 B1	3/97	EP			--
Qm	0 875 754	11-4-98	EP			--
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Qm	1 288 654 A1	03-05-03	EP			--
Qm	2000-121594 abstract	April 00	JP			--
Qm	56100451	Aug 81	JP			yes (abstract)
Qm	11297890	Oct. 99	JP			yes (abstract)
Qm	7-66499	3-10-95	JP			yes (abstract)
Qm	7-290751	11-7-95	JP			yes (abstract)
Qm	9-260697	10-3-97	JP			yes (abstract)
Qm	10-241992 abstract	9-1-98	JP			--
Qm	10-303444 abstract	11-1-98	JP			--
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Qm	5-31 5703	11-26-93	JP			yes (abstract)
Qm	10-52780 abstract	2-24-98	JP			yes (abstract)
Examiner	c.j. Arles		Date Considered	16/7/05		

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		APPLICANT BHULLAR et al.	
		FILING DATE 06/20/2003	GROUP 1745-3700
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CJA	116	LPKF MicrolineLaser II, LPKF Laser & Electronics AG; LPKF; Art.-Nr. 107645-2 (01/00) (2pp.)	
CJA	117	Microline Solutions, LPKF Laser & Electronics AG; LPKF; Art.-Nr. 107658-1 (01/00) (3pp.)	
Examiner <i>A. Janes</i>		Date Considered <i>11/7/05</i>	

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INFORMATION DISCLOSURE STATEMENT					APPLICANT BHULLAR et al.		
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1.1	86	WO 91/02391	2-21-91	PCT		--	
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Opn	88	WO 95/22881	8-24-95	PCT		--	
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Epa	91	WO 99/13101	3-18-99	PCT		--	
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Opn	94	WO 98/55856	12-10-98	PCT		--	
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Opn	96	WO 00/73778	12/2000	PCT		--	
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Cja	98	WO 01/36953	5-25-01	PCT		yes abstract	
Opn	99	WO 01/75438	10-11-01	PCT		--	
Opn	100	WO 01/25775	4-12-01	PCT		--	
Opn	101	WO 01/92884	12-6-01	PCT		yes abstract	
Epa	102	WO 02/086483	10-31-02	PCT		yes abstract	
Cja	103	WO 02/27074	4-4-02	PCT		yes abstract	
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*Examiner Initial	105	Tender, L. et al., "Electrochemical Patterning of Self-Assembled Monolayers onto Microscopic Arrays of Gold Electrodes Fabricated by Laser Ablation, <i>Langmuir</i> , 1996, 12, 5515-5518.					
Opn	106	Tahhan, Isam, "Biocompatible Microstructuring of Polymers and Electrodes with an Excimer Laser", MEDICS Workshop 2000 Speakers Abstracts, 2 pp.					
Opn	107	Sheppard, Jr. et al. "Electrical Conductivity Measurements Using Microfabricated Interdigitated Electrodes", <i>Anal. Chem.</i> , 1993, 65, 1199-1202.					
Opn	108	Srinivasan R., et al. "Ultraviolet Laser Ablation of Organic Polymers", <i>Chem. Rev.</i> , 1989, 89, 1303-1316.					
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Opn	115	Duley, W.W. "UV Lasers: effects and applications in materials science", Chapter 3 Photochemical and photothermal effects, Cambridge University Press, pages 78-97.					
Examiner	C.J. Culver				Date Considered	15/10/05	
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Complete if Known

U.S. PATENT DOCUMENTS

Examiner Initials*	Cite No. ¹	Foreign Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or Application of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T*
		Country Code ² -Number ³ -Kind Code ⁵ (if known)				
04	1	JP 189675 (abstract)	1997-04-22	Matsushita Electric Ind Col Ltd..		X

Examiner Signature		Date Considered	4/17/05
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